

Serial No. 10/701,864

Docket No. 200312367-1

OCT 30 2006

**AMENDMENTS TO THE SPECIFICATION**

Please replace the paragraph beginning on page 1, line 4, with the following amended paragraph:

This application is related to co-pending and commonly assigned U.S. Patent Application to Wang et al., which was filed on November 5, 2003, contemporaneously with this application and entitled "SYSTEM AND METHOD FOR DETERMINING S-PARAMETERS USING A MATCHED LOAD," Serial No. 10/701,907, now U.S. Patent No. 6,998,833, the disclosure of which is incorporated herein by reference.

Please replace the paragraph beginning on page 12, line 6, of the Specification with the following amended paragraph:

FIG. 4 illustrates a system 40 for determining S-parameters according to an aspect of the present invention. The system 40 includes an S-parameter calculator 42 that implements an algorithm (e.g., equations) for determining reflection coefficients and S-parameters of a DUT. The S-parameter calculator 42 can be implemented as computer executable instructions, for example, running in a computer, workstation, network analyzer or other test equipment, such that the S-parameters of the DUT can be computed and stored in memory of the computer, workstation, network analyzer, or test equipment. The system 40 can also include a user interface 44 associated with the S-parameter calculator 42, such as a graphical user interface (GUI). The user interface 44 provides a programmable mechanism to receive user inputs 46 for establishing operating parameters associated with the S-parameter calculator 42. For example, the user inputs 46 can define structural and/or functional characteristics associated with a DUT for which S-parameters are to be determined. The user inputs can also establish procedures for implementing verification of the S-parameter results.